

Notice of References Cited

Application/Control No.

10/038,600

Applicant(s)/Patent Under
Reexamination
LEE, TU

Examiner

Yelena G. Gakh, Ph.D.

Art Unit

1743

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sung et al. "Phase separation in thin film polymer blends with and without block copolymer additives" ✓
	V	Lu et al. "Nondestructive imaging of dielectric-constant profiles and ferroelectric domains with a scanning-tip microwave near-field microscope", Science, 1997, vol. 276, pp. 2004-2006 ✓
	W	Hobbs et al. "Experimentally determined temperatures-concentration phase diagrams of monodisperse alkanes with chains containing between 100 and 200 carbons", J. Polymer Sci., Part B., 1999, v. 37, pp. 3186-3200 ✓
	X	Xiang "Combinatorial materials synthesis and screening: an integrated materials chip approach to discovery and optimization of functional materials", Annu. Rev. Mater. Sci., 1999, v. 29, pp. 149-71 ✓

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	V	Meredith et al. "Combinatorial measurements for polymeric coatings", Book of Abstracts, 219th ACS National Meeting, San Francisco, CA, March 26-30, 2000 (2000), MTL5-003 American Chemical Society Washington, D. C.
	W	Raghavan et al. "Mapping polymer heterogeneity using atomic force microscopy phase imaging and nanoscale indentation", Macromolecules, 2000, v. 33, pp. 2573-2583
	X	Russek et al. "Magnetic combinatorial thin-film libraries", IEEE Transactions on MAGnetics, 2001, v. 37, (4, Pt.1), pp. 2156-215

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